

P45N02LI

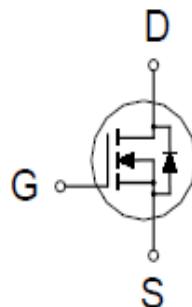
N-Channel Logic Level Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
25V	20mΩ @ $V_{GS} = 10V$	26A



TO-251



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ C$	I_D	26	A
	$T_C = 100^\circ C$		16	
Pulsed Drain Current ¹		I_{DM}	70	
Avalanche Current		I_{AS}	13	
Avalanche Energy	$L = 0.1 \text{ mH}$	E_{AS}	9	mJ
Power Dissipation	$T_C = 25^\circ C$	P_D	22	W
	$T_C = 100^\circ C$		8.9	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		5.6	°C / W
Junction-to-Ambient	$R_{\theta JA}$		70	

¹Pulse width limited by maximum junction temperature.

²Duty Cycle ≤ 1%.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1	1.6	2.5	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$			25	μA
		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			250	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	70			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 10\text{A}$		21	41	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 15\text{A}$		14	20	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 15\text{V}, I_D = 15\text{A}$		30		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 12.5\text{V}, f = 1\text{MHz}$		529		pF
Output Capacitance	C_{oss}			100		
Reverse Transfer Capacitance	C_{rss}			76		
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 12.5\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 15\text{A}$		12		nC
Gate-Source Charge ²	Q_{gs}			2.3		
Gate-Drain Charge ²	Q_{gd}			3		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 12.5\text{V}, I_D \geq 15\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		18		nS
Rise Time ²	t_r			17		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			38		
Fall Time ²	t_f			10		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				26	A
Forward Voltage ¹	V_{SD}	$I_F = 15\text{A}, V_{\text{GS}} = 0\text{V}$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 15\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		15		nS
Reverse Recovery Charge	Q_{rr}			6		nC

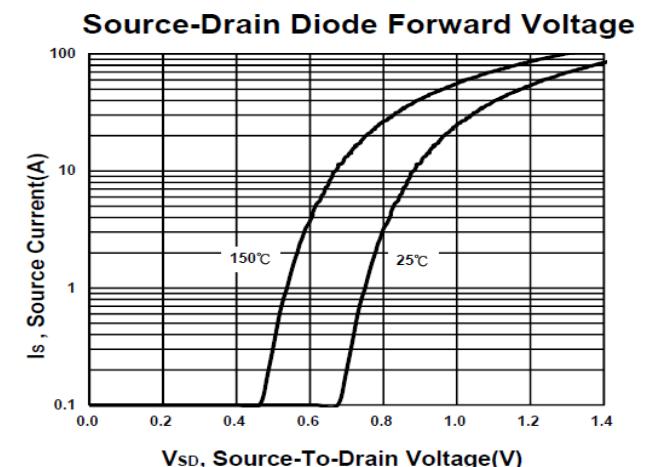
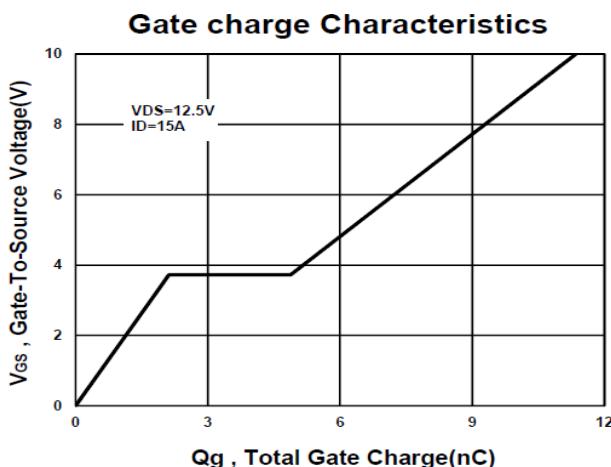
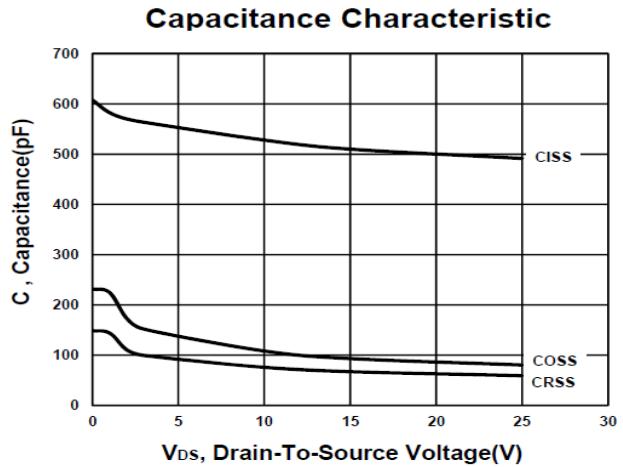
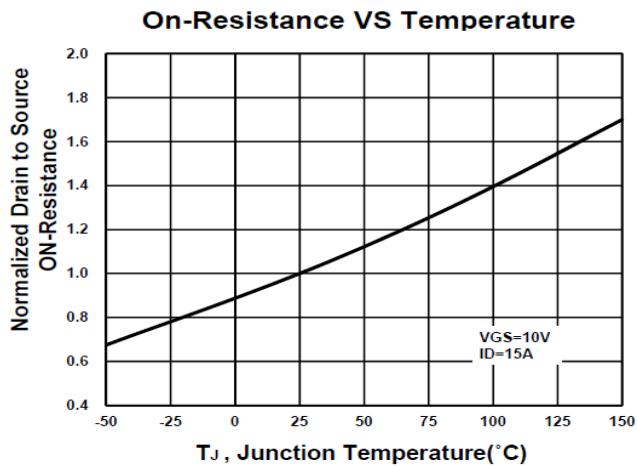
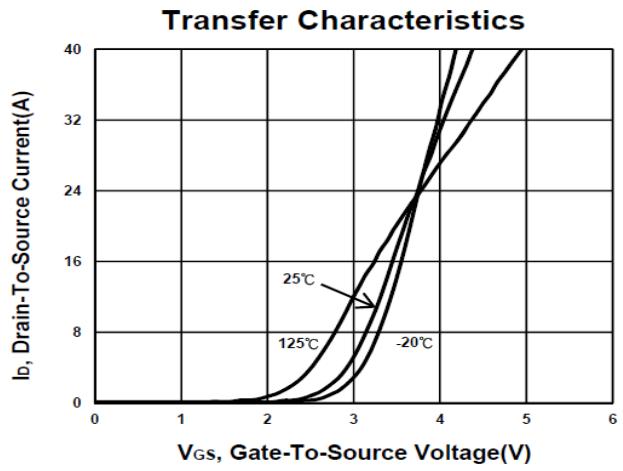
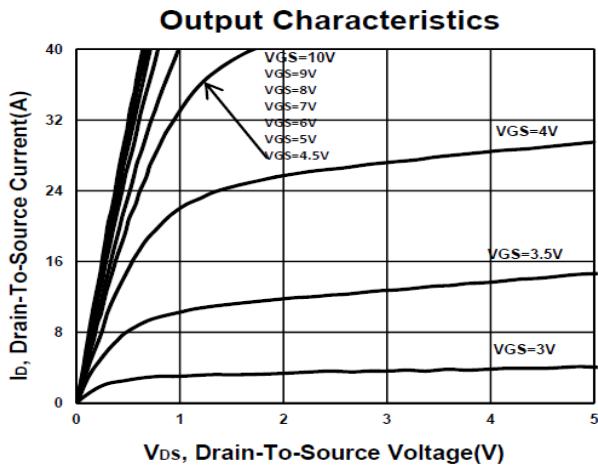
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

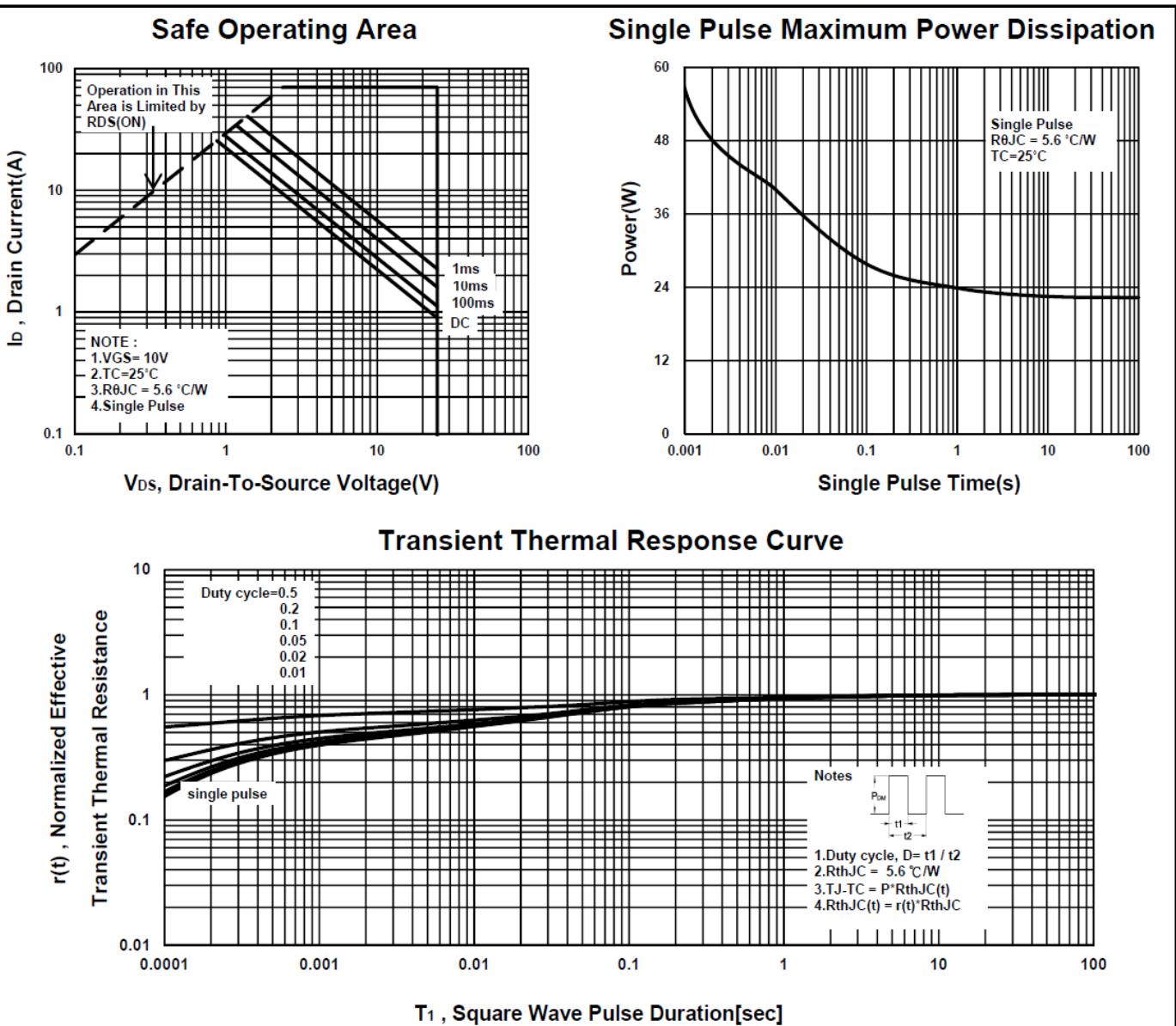
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Package Dimension

TO-251 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	14	15	17.14	H	0.89		1.7
B	2.1	2.3	2.5	I	6.3		6.8
C	0.4	0.5	0.6	J	4.8		5.5
D	0.35	0.5	0.65	K	0.5	0.84	1.14
E	0.9	1.1	1.5	L	0.4	0.76	0.912
F	7		9.65	M		2.3	
G	5.3		6.22	N	1.4	2.16	2.23

